

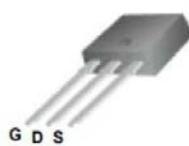


First Semiconductor

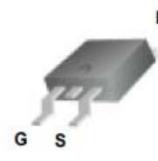
700V N-Channel MOSFET

FIR4N70BPG/LG**Features:**

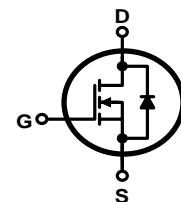
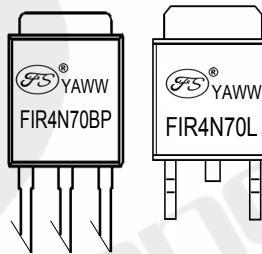
- Low Intrinsic Capacitances.
- Excellent Switching Characteristics.
- Extended Safe Operating Area.
- Unrivalled Gate Charge : $Q_g=15\text{nC}$ (Typ.).
- $\text{BVDSs}=700\text{V}, I_D=4\text{A}$
- $R_{DS(on)}: 2.6 \Omega$ (Max) @ $V_G=10\text{V}$
- 100% Avalanche Tested

PIN Connection TO-251/252

TO-251



TO-252

Schematic diagram**Marking Diagram**

Y	= Year
A	= Assembly Location
WW	= Work Week
FIR4N70BP/L	= Specific Device Code

Absolute Maximum Ratings ($T_a=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage	700	V
I_D	Drain Current	$T_j=25^\circ\text{C}$	4.0
		$T_j=100^\circ\text{C}$	2.3
$V_{GS(TH)}$	Gate Threshold Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note1)	300	mJ
I_{AR}	Avalanche Current (note2)	4	A
P_D	Power Dissipation ($T_j=25^\circ\text{C}$)	50	W
T_j	Junction Temperature(Max)	150	$^\circ\text{C}$
T_{stg}	Storage Temperature	-55~+150	$^\circ\text{C}$
TL	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance,Junction to Case	-	2.50	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance,Junction to Ambient	-	110	$^\circ\text{C}/\text{W}$



Electrical Characteristics (Ta=25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0	700	-	-	V
△BV _{DSS} /△TJ	Breakdown Voltage Temperature Coefficient	I _D =250μA, Reference to 25°C	-	0.6	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =700V, V _{GS} =0V	-	-	1	μA
		V _{DS} =560V, T _j =125°C			10	
I _{GSSF}	Gate-body leakage Current, Forward	V _{GS} =+30V, V _{DS} =0V	-	-	100	nA
I _{GSSR}	Gate-body leakage Current, Reverse	V _{GS} =-30V, V _{DS} =0V	-	-	-100	
On Characteristics						
V _{GS(TH)}	Date Threshold Voltage	I _D =250μA, V _{DS} =V _{GS}	2	-	4	V
R _{DS(ON)}	Static Drain-Source On-Resistance	I _D =2A, V _{GS} =10V	-	-	2.6	Ω
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0, f=1.0MHz	-	480	590	pF
C _{oss}	Output Capacitance		-	65	85	
C _{rss}	Reverse Transfer Capacitance		-	5.6	7.3	
Switching Characteristics						
T _{d(on)}	Turn-On Delay Time	V _{DD} =350V, I _D =4A R _G =25Ω (Note 3,4)	-	13	35	nS
T _r	Turn-On Rise Time		-	45	110	
T _{d(off)}	Turn-Off Delay Time		-	25	60	
T _f	Turn-Off Rise Time		-	35	80	
Q _g	Total Gate Charge	V _{DS} =480V, V _{GS} =10V, I _D =4A (Note 3,4)	-	15	20	nC
Q _{gs}	Gate-Source Charge		-	3.4	-	
Q _{gd}	Gate-Drain Charge		-	7.1	-	
Drain-Source Diode Characteristics and Maximum Ratings						
I _s	Max. Diode Forward Current	-	-	-	4	A
I _{SM}	Max. Pulsed Forward Current	-	-	-	16	
V _{SD}	Diode Forward Voltage	I _D =4A	-	-	1.4	V
T _{rr}	Reverse Recovery Time	I _s =4A, V _{GS} =0V diF/dt=100A/μs (Note 3)	-	250	-	nS
Q _{rr}	Reverse Recovery Charge		-	1.5	-	μC

Notes : 1, L=27.5mH, IAS=4A, VDD=50V, RG=25Ω, Starting TJ =25°C

2, Repetitive Rating : Pulse width limited by maximum junction temperature

3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%

4, Essentially Independent of Operating Temperature

Typical Characteristics

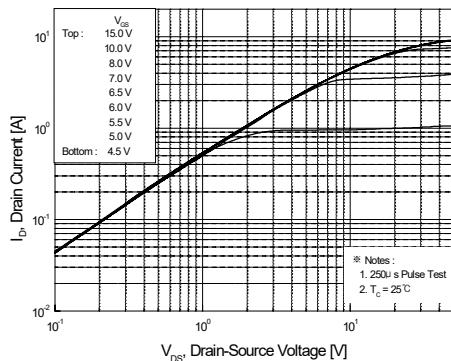


Figure 1. On-Region Characteristics

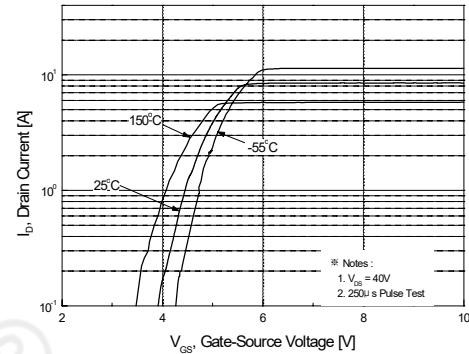


Figure 2. Transfer Characteristics

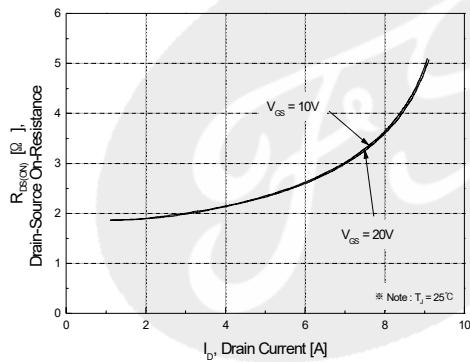


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

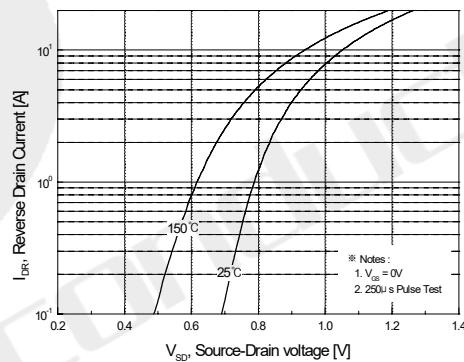


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

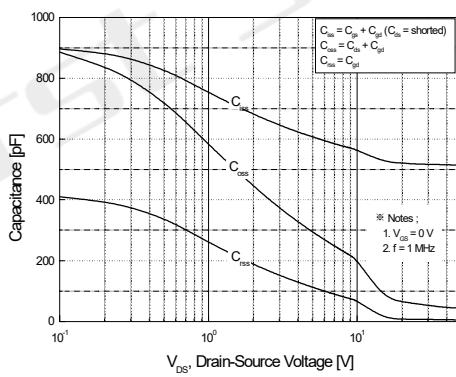


Figure 5. Capacitance Characteristics

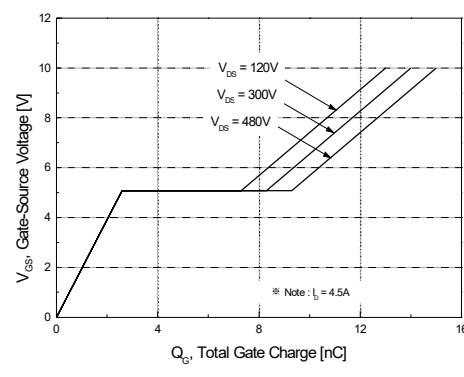
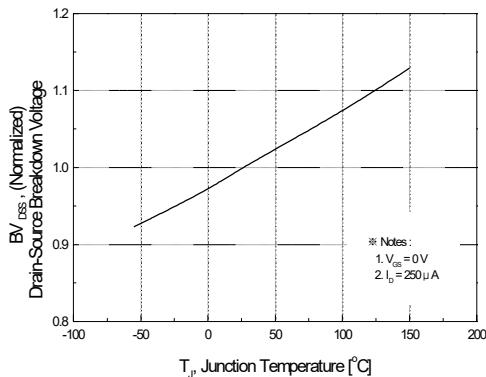
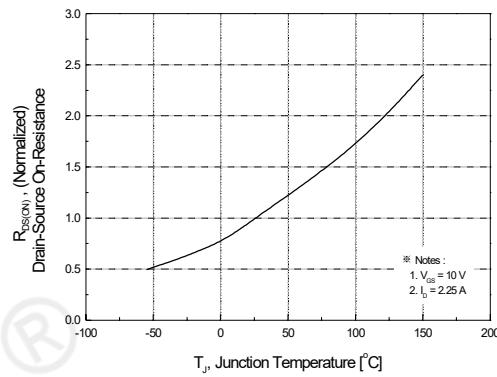


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)



**Figure 7. Breakdown Voltage Variation
vs Temperature**



**Figure 8. On-Resistance Variation
vs Temperature**

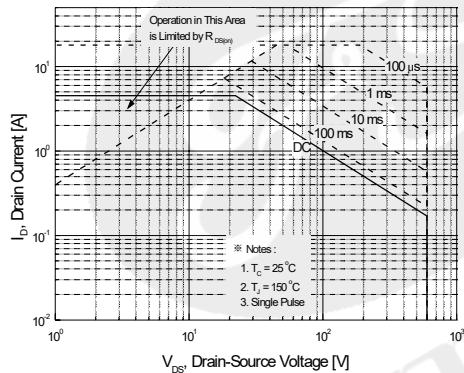
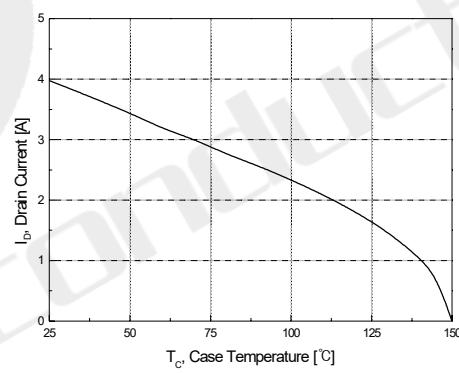


Figure 9-1. Maximum Safe Operating Area



**Figure 10. Maximum Drain Current
vs Case Temperature**

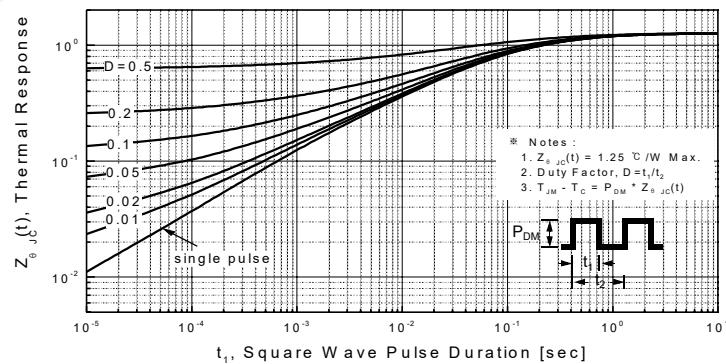
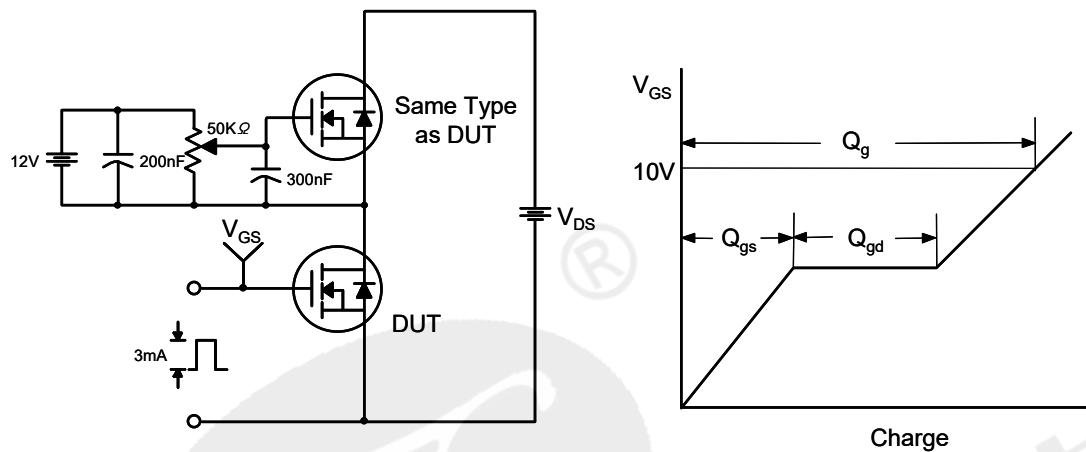
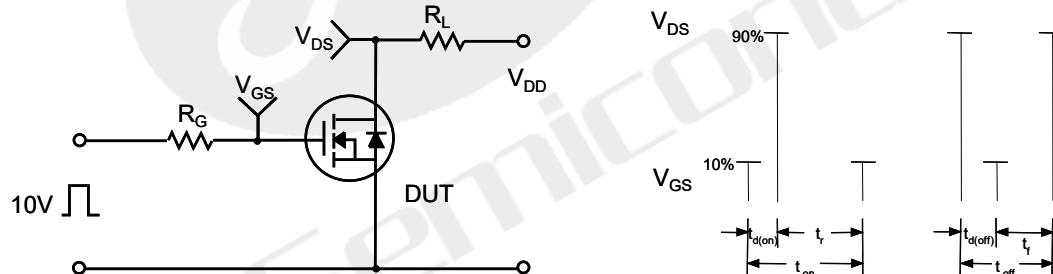
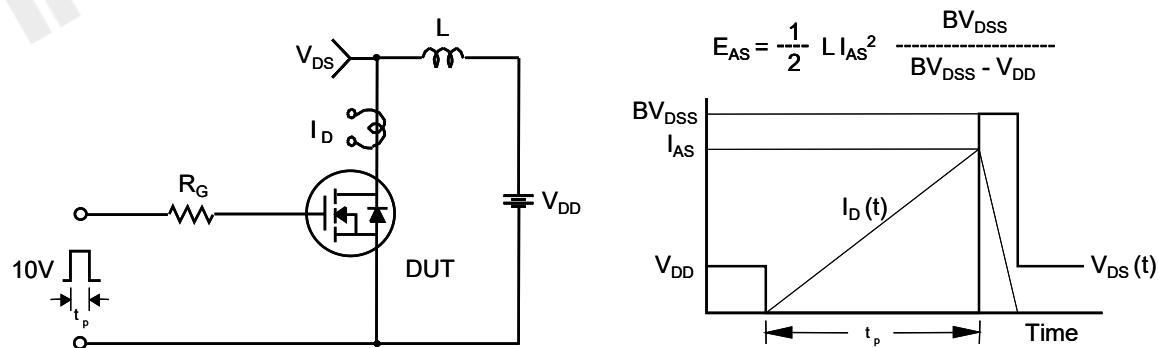
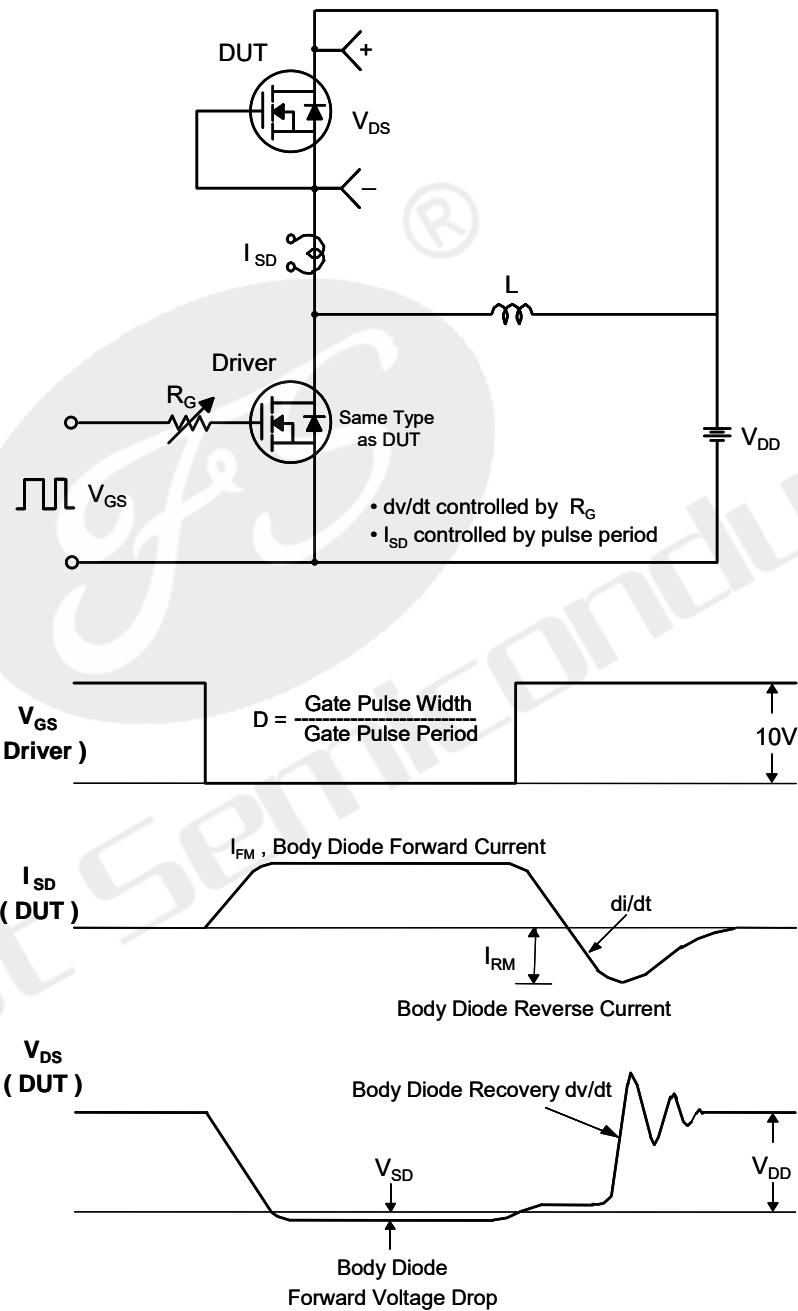


Figure 11-1. Transient Thermal Response Curve

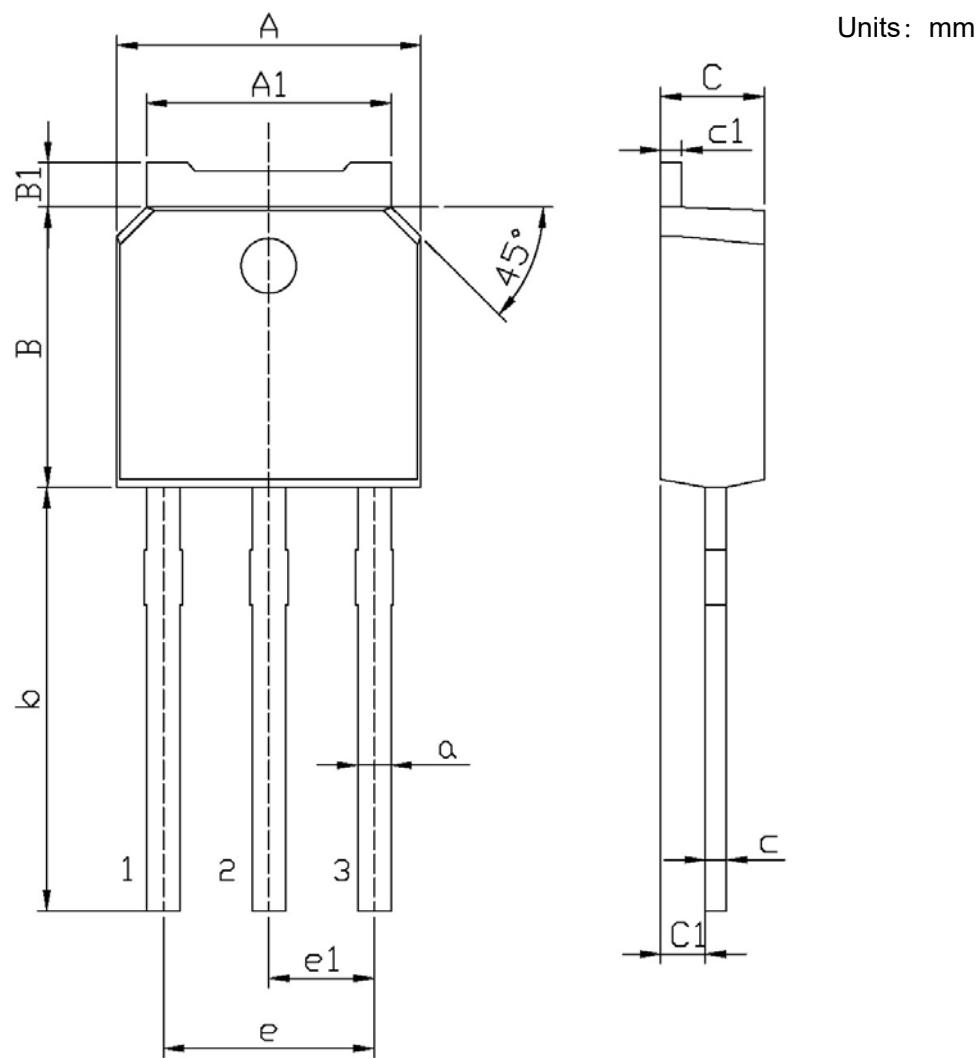
Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching Test Circuit & Waveforms


Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Dimension

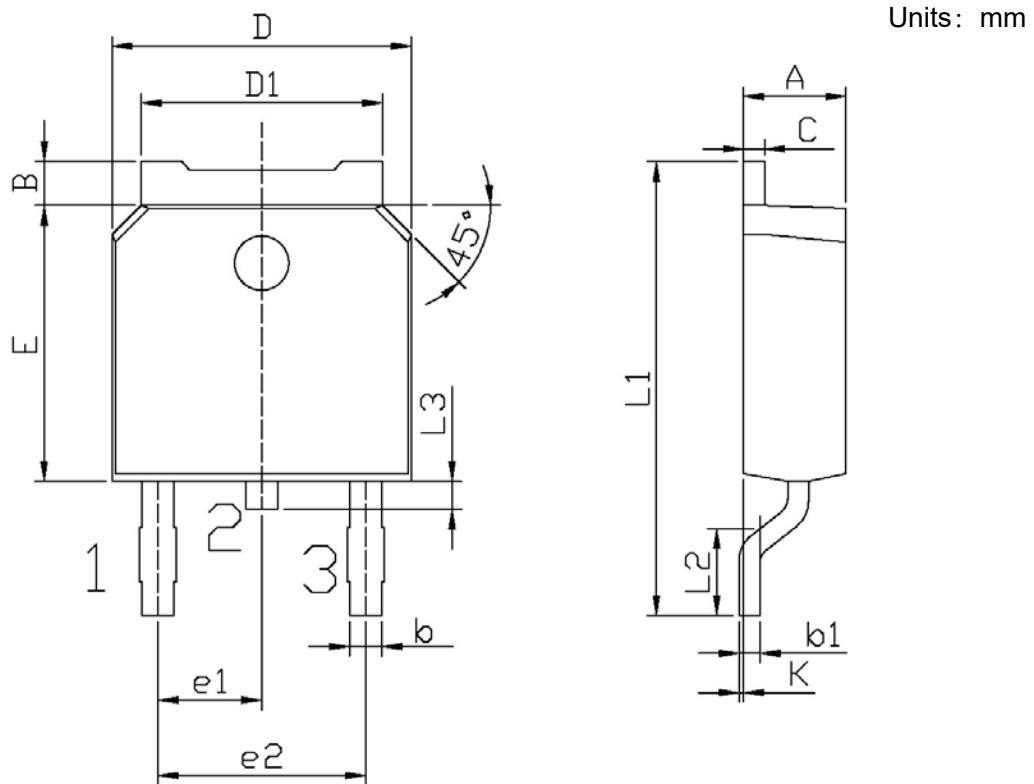
TO-251



Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min	Max		Min	Max
A	6.45	6.75	a	0.70	0.90
A1	5.20	5.40	b	9.00	9.40
B	5.95	6.25	c	0.45	0.55
B1	0.95	1.25	c1	0.45	0.55
C	2.20	2.40	e1	2.24	2.34
C1	0.95	1.15	e	4.43	4.73

Package Dimension

TO-252



Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min	Max		Min	Max
A	2.20	2.40	E	5.95	6.25
B	0.95	1.25	e1	2.24	2.34
b	0.70	0.90	e2	4.43	4.73
b1	0.45	0.55	L1	9.85	10.35
C	0.45	0.55	L2	1.25	1.75
D	6.45	6.75	L3	0.60	0.90
D1	5.20	5.40	K	0.00	0.10



Declaration

- FIRST reserves the right to change the specifications, the same specifications of products due to different packaging line mold, the size of the appearance will be slightly different, shipped in kind, without notice! Customers should obtain the latest version information before ordering, and verify whether the relevant information is complete and up-to-date.
- Any semiconductor product under certain conditions has the possibility of failure or failure, The buyer has the responsibility to comply with safety standards and take safety measures when using FIRST products for system design and manufacturing, To avoid potential failure risks, which may cause personal injury or property damage!
- Product promotion endless, our company will wholeheartedly provide customers with better products!

ATTACHMENT

Revision History

Date	REV	Description	Page
2018.01.01	1.0	Initial release	